

IGBT

SGP5N60RUF

Short Circuit Rated IGBT

General Description

Fairchild's RUF series of Insulated Gate Bipolar Transistors (IGBTs) provide low conduction and switching losses as well as short circuit ruggedness. The RUF series is designed for applications such as motor control, uninterrupted power supplies (UPS) and general inverters where short circuit ruggedness is a required feature.

Features

- Short circuit rated 10us @ $T_C = 100$ °C, $V_{GE} = 15$ V
- · High speed switching
- Low saturation voltage : $V_{CE(sat)} = 2.2 \text{ V} @ I_C = 5A$
- High input impedance

Applications

AC & DC motor controls, general purpose inverters, robotics, and servo controls.





Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Description		SGP5N60RUF	Units
V _{CES}	Collector-Emitter Voltage		600	V
V _{GES}	Gate-Emitter Voltage		± 20	V
_	Collector Current	$@ T_C = 25^{\circ}C$	8	Α
I _C	Collector Current	@ T _C = 100°C	5	Α
I _{CM (1)}	Pulsed Collector Current		15	Α
	Short Circuit Withstand Time	@ T _C = 100°C	10	us
T _{SC} P _D	Maximum Power Dissipation	@ T _C = 25°C	60	W
	Maximum Power Dissipation	@ T _C = 100°C	25	W
TJ	Operating Junction Temperature		-55 to +150	°C
T _{stg}	Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temp. for Soldering Purposes, 1/8" from Case for 5 Seconds		300	°C

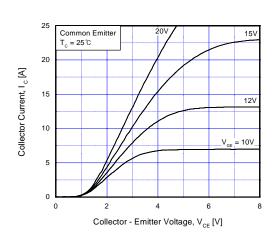
Notes

(1) Repetitive rating : Pulse width limited by max. junction temperature

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Parameter Test Conditions		Тур.	Max.	Units
Off Chai	racteristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	or-Emitter Breakdown Voltage $V_{GE} = 0V, I_{C} = 250uA$				V
ΔB _{VCES} / ΔT _J	Temperature Coefficient of Breakdown Voltage	V _{GE} = 0V, I _C = 1mA		0.6		V/°C
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0V$			250	uA
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0V$			± 100	nA
On Char	racteristics					
V _{GE(th)}	G-E Threshold Voltage	$I_C = 5mA$, $V_{CE} = V_{GE}$	5.0	6.0	8.5	V
	Collector to Emitter	$I_C = 5A$, $V_{GE} = 15V$		2.2	2.8	V
$V_{CE(sat)}$	Saturation Voltage	$I_C = 8A$, $V_{GE} = 15V$		2.5		V
Dynamic	c Characteristics	, 0			1	
C _{ies}	Input Capacitance	.,		354		pF
C _{oes}	Output Capacitance	$V_{CE} = 30V, V_{GE} = 0V,$		67		pF
C _{res}	Reverse Transfer Capacitance	f = 1MHz		14		pF
t _{d(on)}	Turn-On Delay Time			13		ns
	Rise Time	-		24		
t _r	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 5\text{A},$		34	50	ns ns
t _{d(off)} t _f	Fall Time	$V_{CC} = 300 \text{ V}, I_{C} = 3A,$ $R_{G} = 40\Omega, V_{GE} = 15V,$		136	200	ns
E _{on}	Turn-On Switching Loss	Inductive Load, $T_C = 25^{\circ}C$		88		uJ
E _{off}	Turn-Off Switching Loss			107		uJ
E _{ts}	Total Switching Loss	-		195	280	uJ
t _{d(on)}	Turn-On Delay Time			13		ns
t _r	Rise Time	-		26		ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 300 \text{ V}, I_{C} = 5\text{A},$		40	60	ns
t _f	Fall Time	$R_G = 40\Omega$, $V_{GE} = 15V$,		250	350	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 125°C		103		uJ
E _{off}	Turn-Off Switching Loss	1		220		uJ
E _{ts}	Total Switching Loss	1		323		uJ
T _{sc}	Short Circuit Withstand Time	V _{CC} = 300 V, V _{GE} = 15V @ T _C = 100°C	10			us
Q _q	Total Gate Charge			16	24	nC
Q _{qe}	Gate-Emitter Charge	$V_{CE} = 300 \text{ V}, I_{C} = 5A,$		3	6	nC
Q _{gc}	Gate-Collector Charge	V _{GE} = 15V		7	14	nC
L _e	Internal Emitter Inductance	Measured 5mm from PKG		7.5		nH



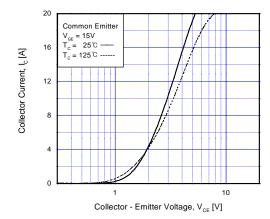
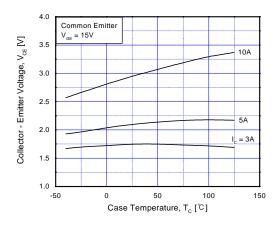


Fig 1. Typical Output Characteristics

Fig 2. Typical Saturation Voltage Characteristics



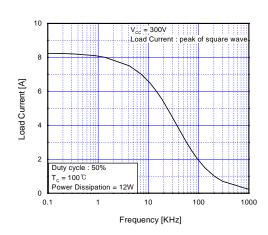
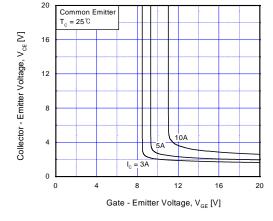


Fig 3. Saturation Voltage vs. Case
Temperature at Variant Current Level

Fig 4. Load Current vs. Frequency



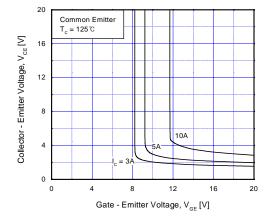


Fig 5. Saturation Voltage vs. V_{GE}

Fig 6. Saturation Voltage vs. V_{GE}

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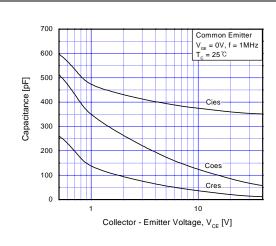


Fig 7. Capacitance Characteristics



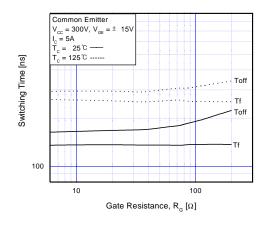


Fig 9. Turn-Off Characteristics vs.
Gate Resistance

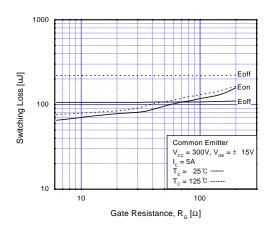


Fig 10. Switching Loss vs. Gate Resistance

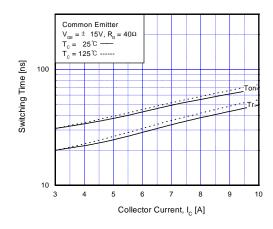


Fig 11. Turn-On Characteristics vs. Collector Current

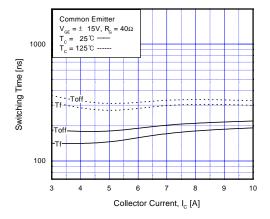
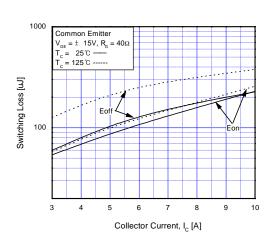


Fig 12. Turn-Off Characteristics vs. Collector Current

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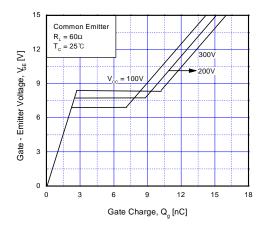
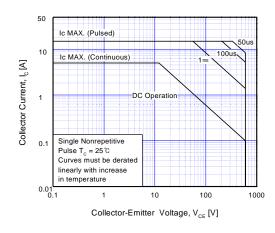


Fig 13. Switching Loss vs. Collector Current

Fig 14. Gate Charge Characteristics



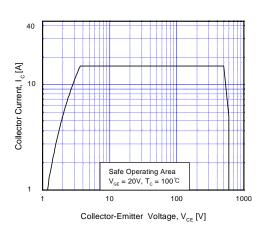


Fig 15. SOA Characteristic

Fig 16. Turn-Off SOA Characteristics

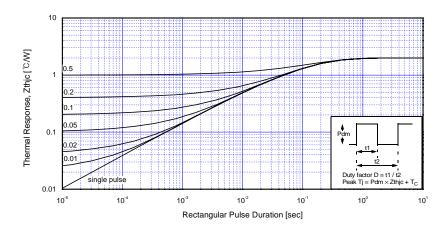
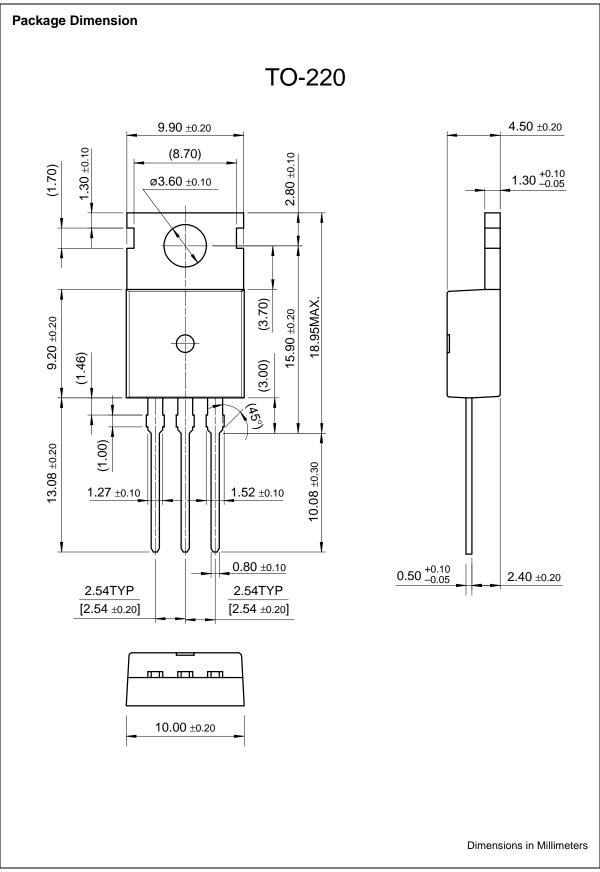


Fig 17. Transient Thermal Impedance of IGBT

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
SGP5N60RUFTU	Full Production	\$1.28	TO-220	3	RAIL

^{* 1,000} piece Budgetary Pricing

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